

## C2220X183G5TACTU

Aliases (C2220X183G5TAC7800)

SMD Comm X8G HT150C Flex, Ceramic, 0.018 uF, 2%, 50 VDC, X8G, SMD, MLCC, High Temperature, Ultra-Stable, 2220, 3.5 mm



General Information		
Series	SMD Comm X8G HT150C Flex	
Style	SMD Chip	
Description	SMD, MLCC, High Temperature, Ultra-Stable	
Features	High Temperature, Ultra-Stable	
RoHS	Yes	
Termination	Flexible Termination	
Marking	No	
AEC-Q200	No	
Typical Component Weight	190 mg	
Shelf Life	78 Weeks	
MSL	1	

Dimensions	
Chip Size	2220
L	5.9mm +/-0.75mm
W	5mm +/-0.4mm
Т	1.4mm +/-0.15mm
S	3.5mm MIN
В	0.7mm +/-0.35mm

Packagii Packagir Packagir

	5mm +/-0.4mm	Tolerance	2%
	1.4mm +/-0.15mm	Voltage DC	50 VDC
	3.5mm MIN	Dielectric Withstanding Voltage	125 VDC
	0.7mm +/-0.35mm	Temperature Range	-55/+150°C
		Temp. Coefficient	X8G
ing Specifications		Capacitance Change with	30 ppm/C, 1kHz 1.0Vrms
ing	T&R, 180mm, Plastic Tape	Reference to +25°C and 0 VDC Applied (TCC)	
ing Quantity	1000	Dissipation Factor	0.1% 1 kHz 1.0Vrms

**Specifications** 

Capacitance	0.018 uF
Measurement Condition	1 kHz 1.0Vrms
Tolerance	2%
Voltage DC	50 VDC
Dielectric Withstanding Voltage	125 VDC
Temperature Range	-55/+150°C
Temp. Coefficient	X8G
Capacitance Change with Reference to +25°C and 0 VDC Applied (TCC)	30 ppm/C, 1kHz 1.0Vrms
Dissipation Factor	0.1% 1 kHz 1.0Vrms
Aging Rate	0% Loss/Decade Hour: Referee Time is 1000 Hours
Insulation Resistance	55.5556 GOhms

Statements of suitability for certain applications are based on our knowledge of typical operating conditions for such applications, but are not intended to constitute - and we specifically disclaim - any warranty concerning suitability for a specific customer application or use. This Information is intended for use only by customers who have the requisite experience and capability to determine the correct products for their application. Any technical advice inferred from this Information or otherwise provided by us with reference to the use of our products is given gratis, and we assume no obligation or liability for the advice given or results obtained.

Generated 05/05/2025 © 2006 - 2025 YAGEO